

Reliability data handbook — Universal model for reliability prediction of electronics components, PCBs and equipment

ICS 21.020; 31.080.01

National foreword

This Published Document reproduces verbatim IEC TR 62380:2004.
The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors, which has the responsibility to:

- aid enquirers to understand the text;
- present to the responsible international/European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
- monitor related international and European developments and promulgate them in the UK.

A list of organizations represented on this committee can be obtained on request to its secretary.

Cross-references

The British Standards which implement international publications referred to in this document may be found in the *BSI Catalogue* under the section entitled “International Standards Correspondence Index”, or by using the “Search” facility of the *BSI Electronic Catalogue* or of British Standards Online.

This Published Document was published under the authority of the Standards Policy and Strategy Committee on 8 November 2004

Summary of pages

This document comprises a front cover, an inside front cover, the IEC TR title page, pages 2 to 90, an inside back cover and a back cover.
The BSI copyright notice displayed in this document indicates when the document was last issued.

Amendments issued since publication

Amd. No.	Date	Comments